Search Notes

Application/Control N	No. Applicant(s)/Patent (Reexamination	under
10/664,855	JAEHNE ET AL.	
Examiner	Art Unit	
Chukwuma O. Nwac	onicha 1621	

	4.				
	SEAR	CHED			
Class	Subclass	Date	Examiner		
560	17	5/22/2005	ler		
564	162	5/22/2005	low		
564	340	5/22/2005	CON		
564	86	5/22/2005	(DV)	\	6
568	39	5/22/2005	Lev	123	L
				4)	
			\ (L
			10 g	(P)	
			M		
		, , , , , , , , , , , , , , , , , , , ,			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
560	17	5/22/2005	Can
564	162	5/22/2005	les
564	340, 86	5/22/2005	Con/
568/39		5/22/2005	low

SEARCH NO (INCLUDING SEARC		')
	DATE	EXMR
EAST	5/22/2005	Cons
INVENTOR NAME SEARCH	5/22/2005	low
STN: STRUCTURE SEARCH	5/22/2005	Con